

The diagram illustrates the components of a scanning electron microscope (SEM). The main column includes the Source (SO), Beam Deflector (BD), Intermediate Lens (IL), Anode (AM), Inlet (IN), Condenser (CO), Pole Piece (PB), Magnet (MT), and Pole Piece (PL). A detailed view of the workpiece (W) shows a grid of cells with labels P1, P2, and C. A coordinate system (X, Y, Z) is shown.

PRIOR ART

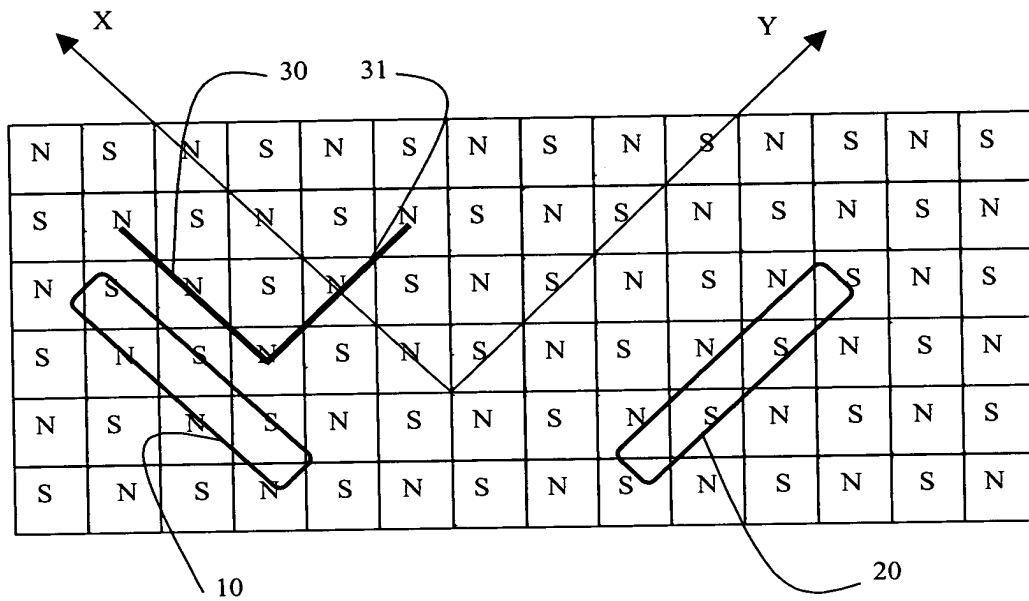


Fig. 2a

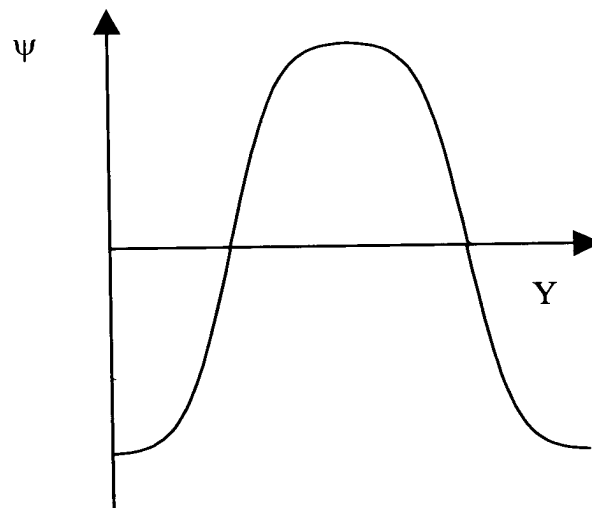


Fig. 2b

S	N	S	N	S	N	S
N	S	N	S	N	S	N
S	N	S	N	S	N	S
N	S	N	S	N	S	N
S	N	S	N	S	N	S
N	S	N	S	N	S	N

Fig. 2c

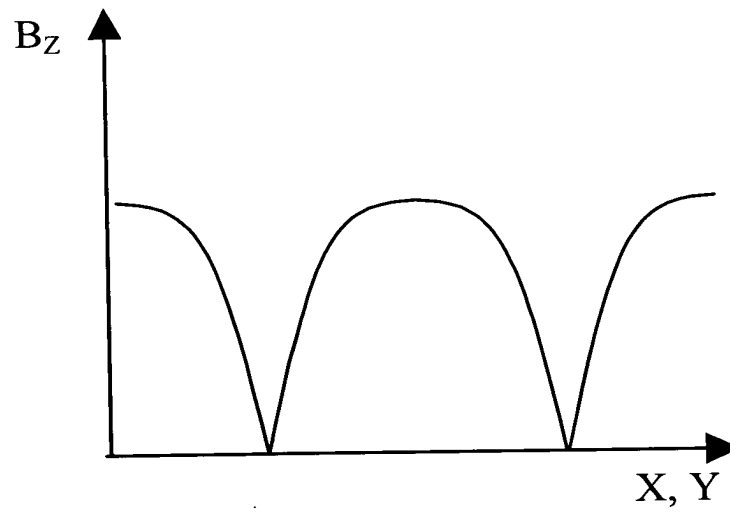


Fig. 2d

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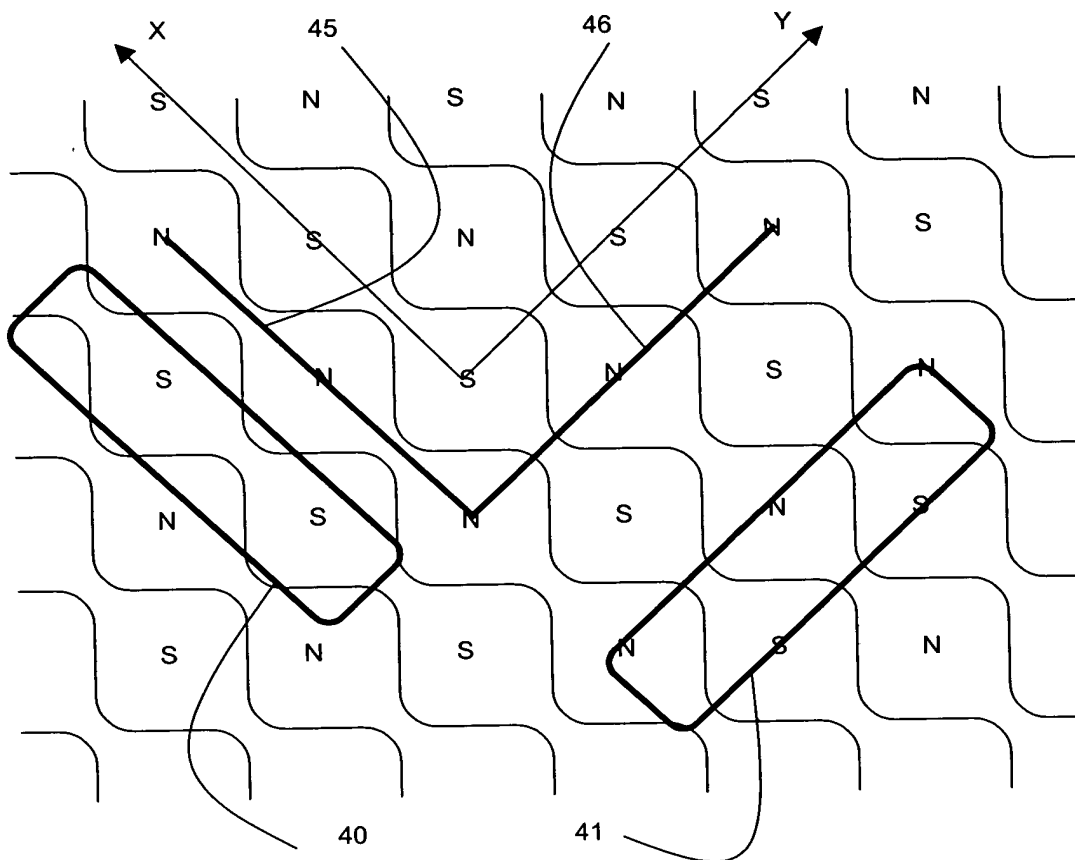


Fig. 3

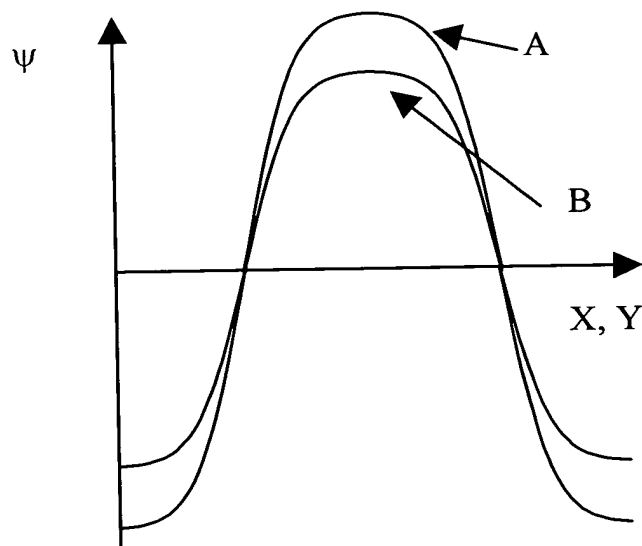


Fig. 4

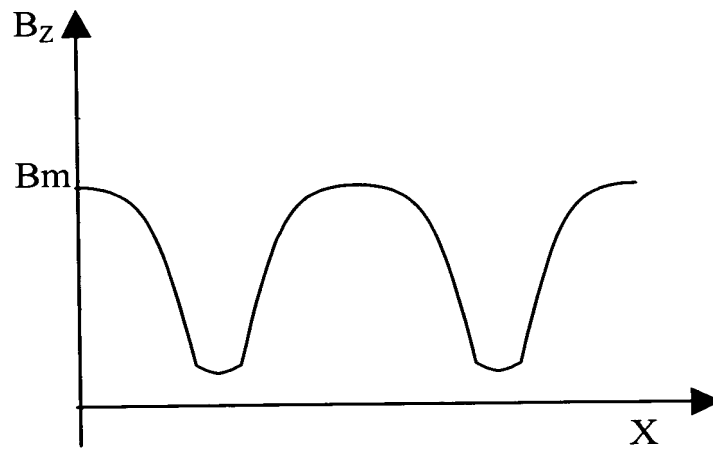


Fig. 5

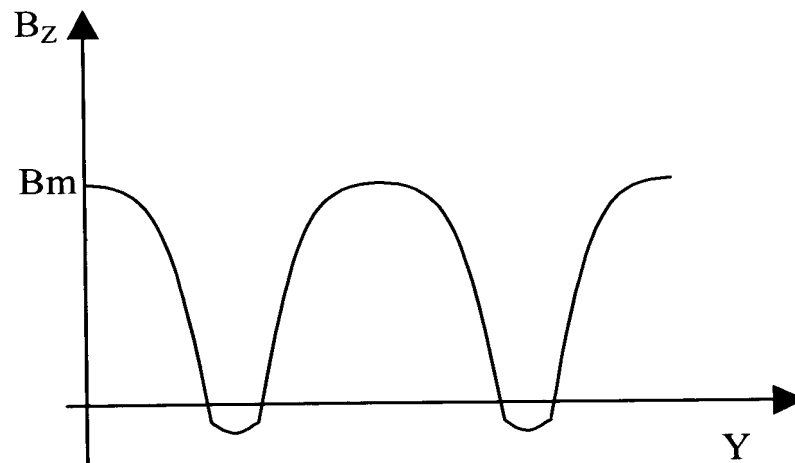


Fig. 6

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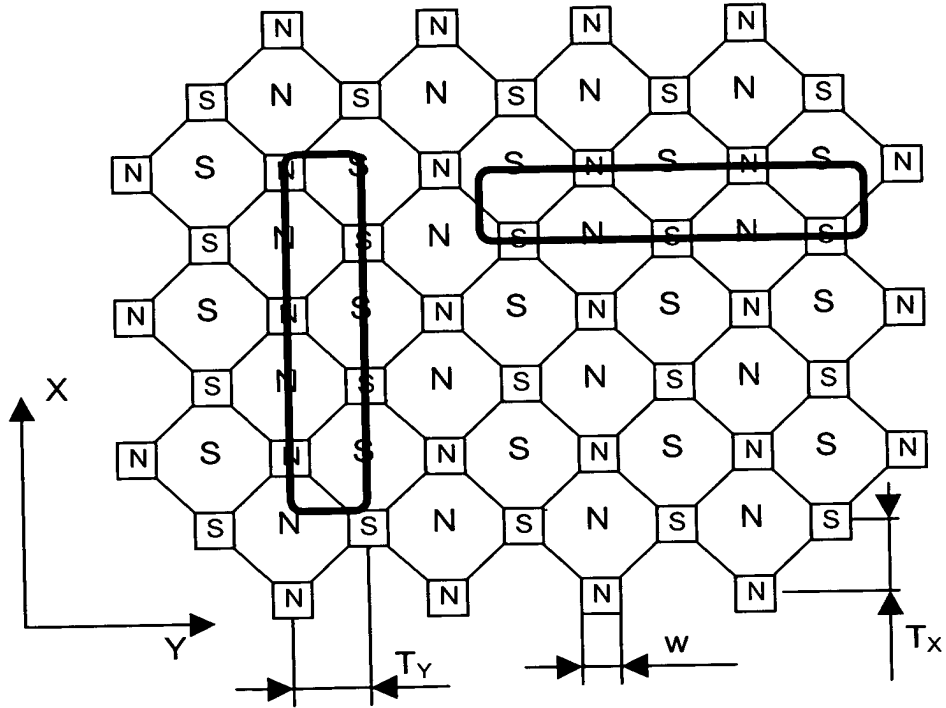


Fig. 7a

PRIOR ART

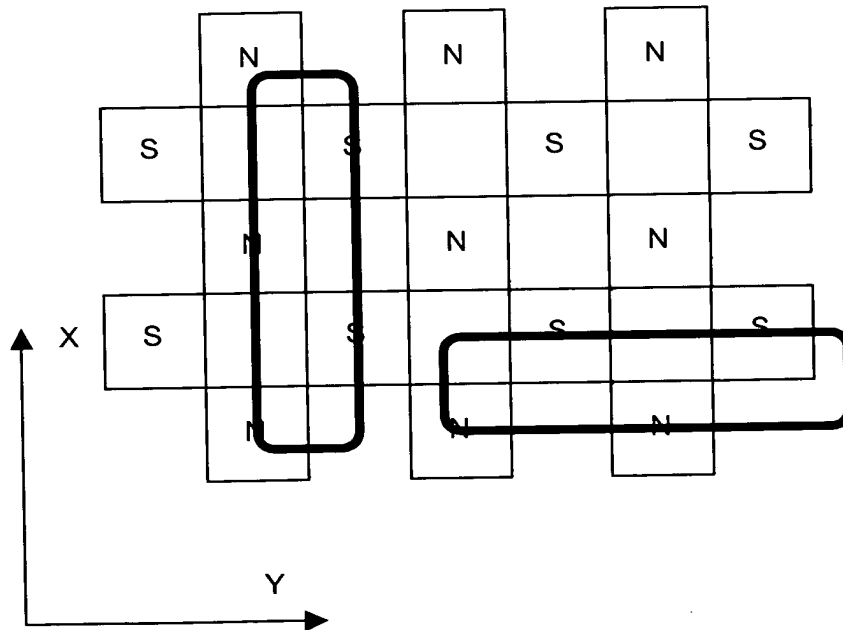


Fig. 7b

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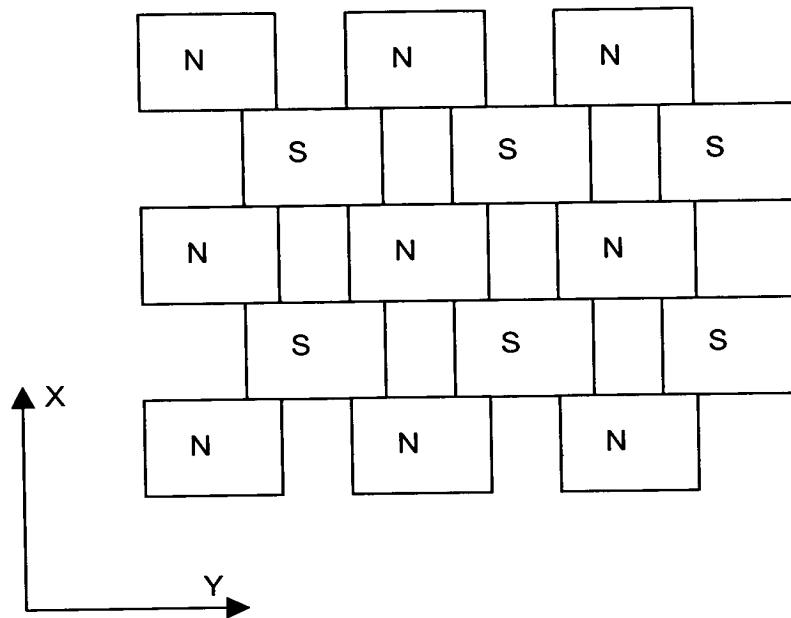


Fig. 7c

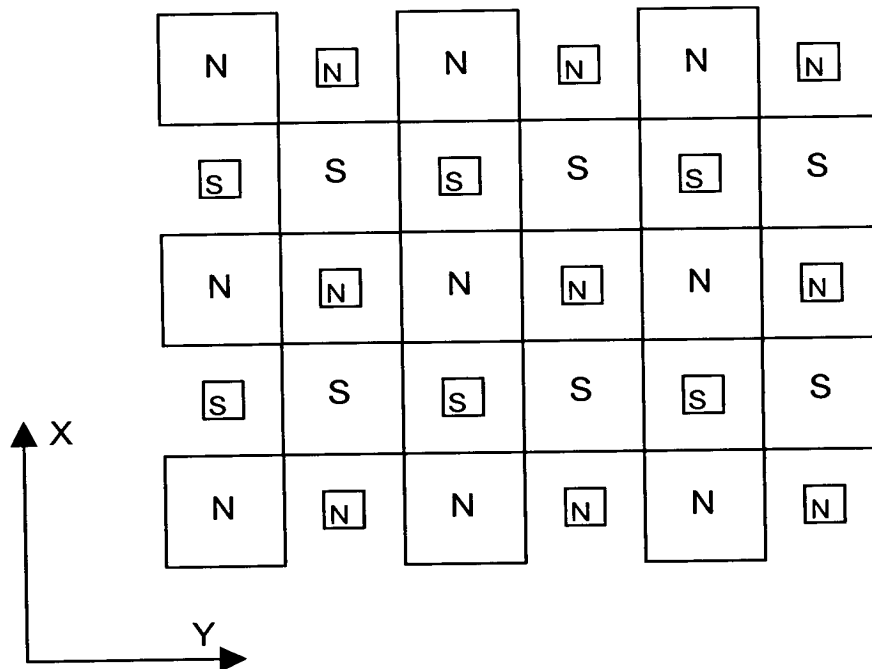


Fig. 7d

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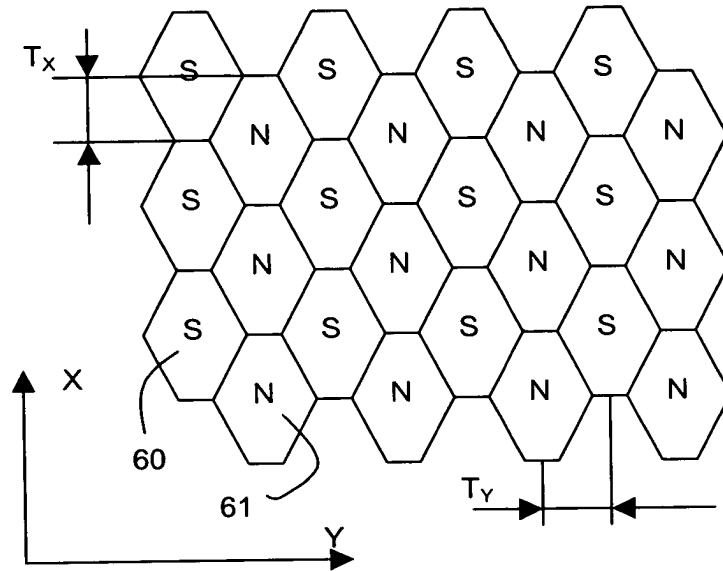


Fig. 8

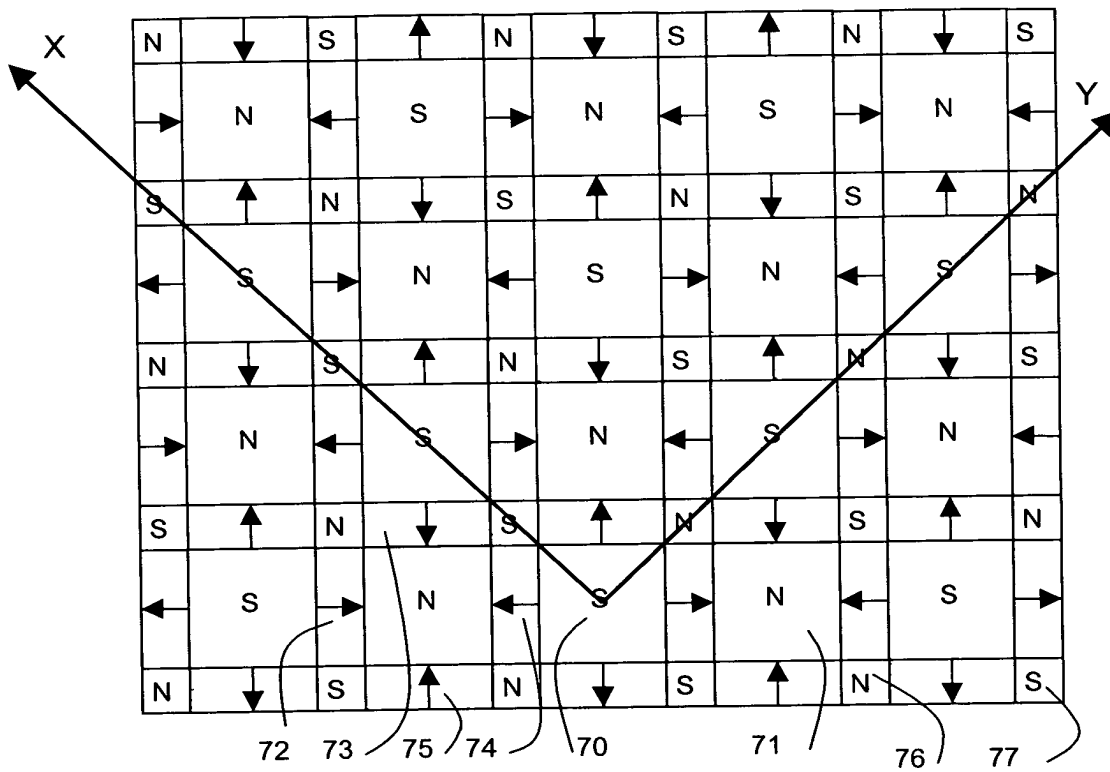


Fig. 9

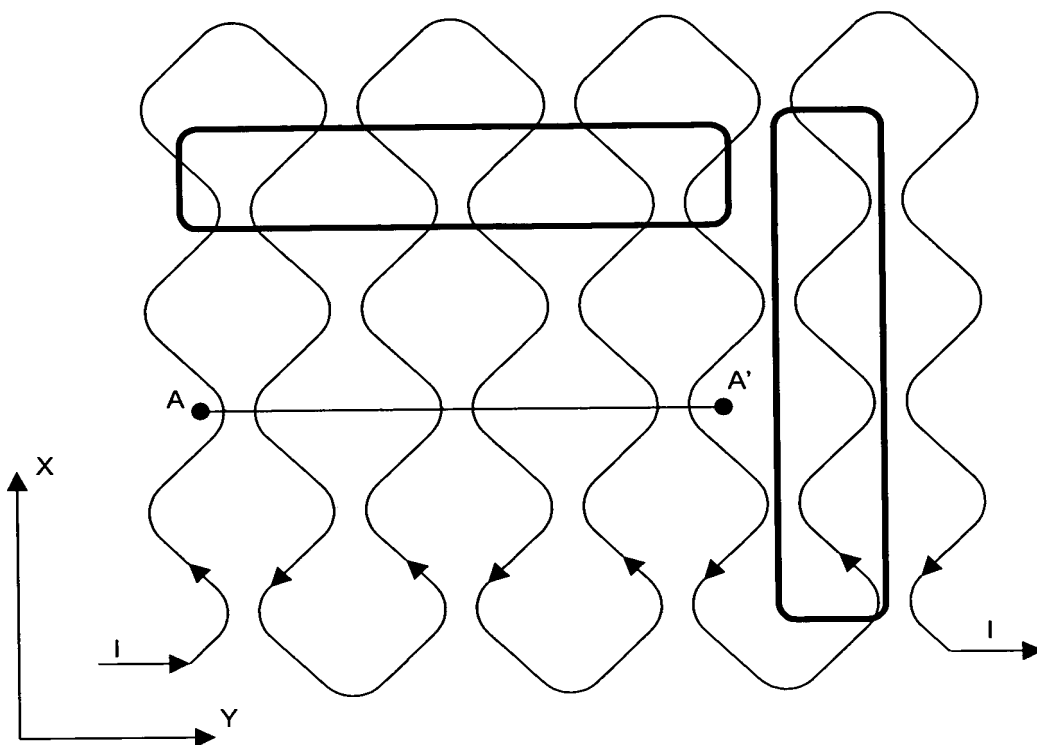


Fig. 10

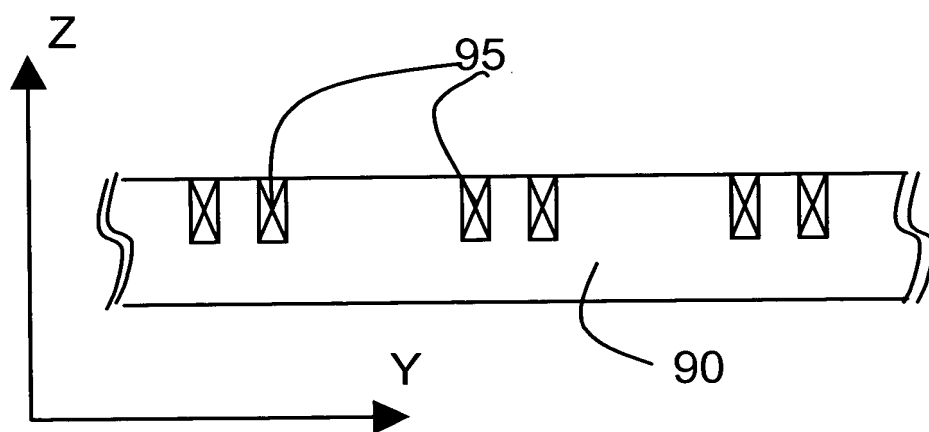


Fig. 11